Seal	rch	No	tes



Application/Control No.	Applicant(s)/Patent under Reexamination
10/050,717	CHEN ET AL.
Examiner	Art Unit
Kanii Batal	2625

SEARCHED				
Class	Subclass	Date	Examiner	
382	254, 284, 287, 318, 319	1/20/2006	КВР	
358	474,505	1/20/2006	КВР	
358	537, 496	1/20/2006	КВР	
358	3.26, 462	6/8/2006	КВР	
399	144	6/8/2006	КВР	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
382	318	6/8/2006	КВР
382	284	6/8/2006	KBP
358	474	6/8/2006	КВР
See Interference Search History Printout		6/8/2006	KBP

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (US-PGB;USPAT;USOCR; EPO;JPO;DERWENT;IBM_TDB	1/3/2006	КВР
EAST (US-PGB;USPAT;USOCR; EPO;JPO;DERWENT;IBM_TDB	1/12/2006	КВР
EAST (USPAT)	1/15/2006	КВР
INVENTOR SEARCH IN PALM	1/21/2006	КВР
EAST (US-PGB;USPAT;USOCR; EPO;JPO;DERWENT;IBM_TDB)	6/8/2006	КВР
NPL-IEEE XPLORE SEARCH	6/8/2006	КВР